

Electron-ion effects at transition -- an obstacle on the upgrade path

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Outline

- Mechanism
 - Electron cloud formation & electron-ion interaction
 - Single-, long bunch vs. multiple, short bunch regime
- Observations
 - Bunch-train dependence of loss, emittance
 - Trailing-edge phenomena
- Mitigation schemes
 - NEG coating
 - RF manipulation
- Discussions

Phenomena

- **Electron-cloud formation**
 - Vacuum pressure rise
 - Electron flux
 - > Occurs when the peak beam current is high (near transition, common IR area)
- **Electron-ion interaction**
 - Beam loss
 - Transverse instability
 - Transverse emittance growth
 - Longitudinal profile variation
 - Tune shift
 - > Significant at transition, lack of Landau damping

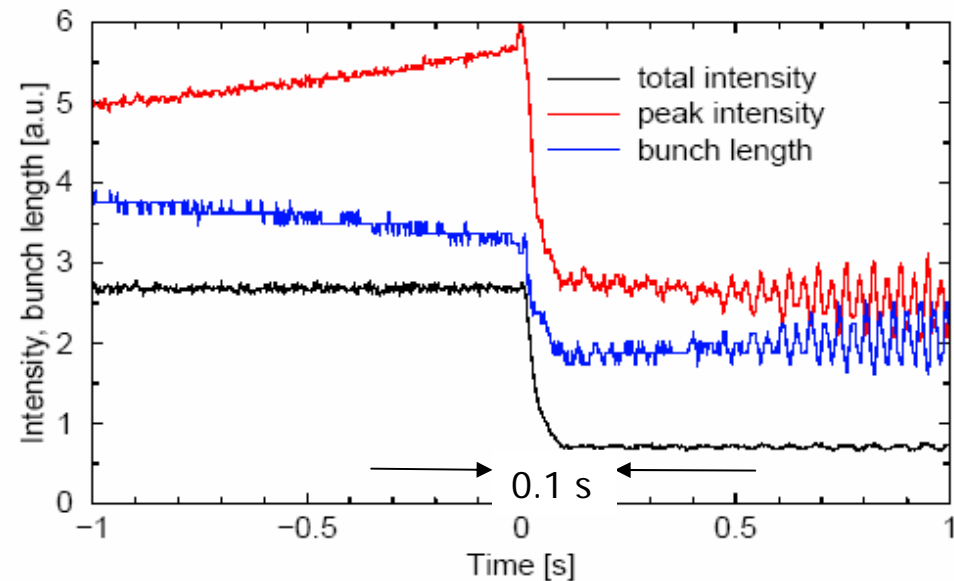
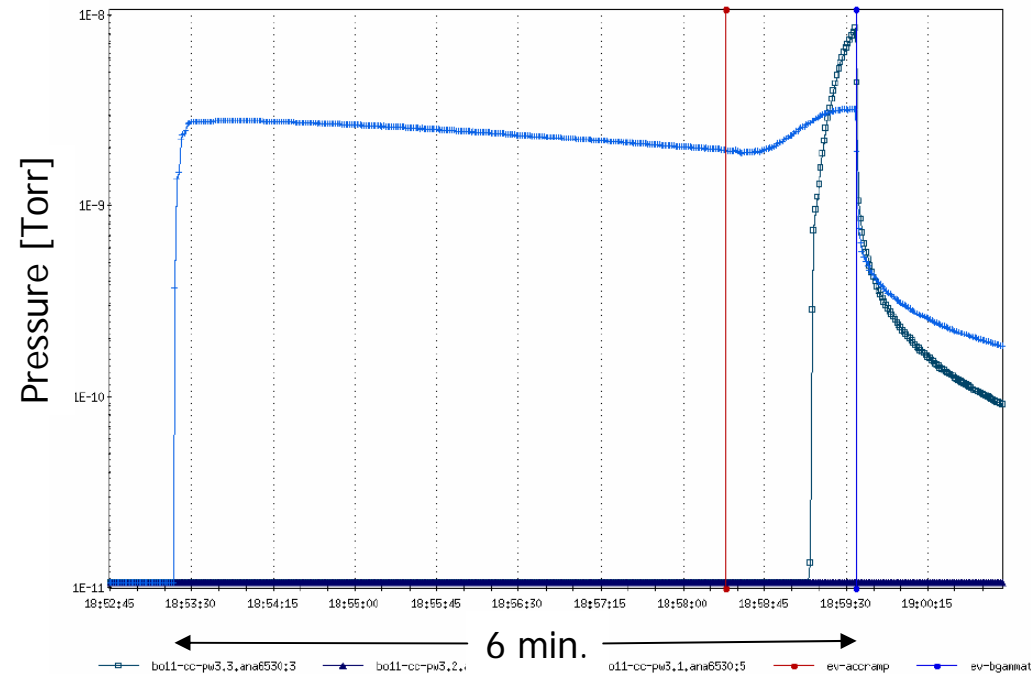
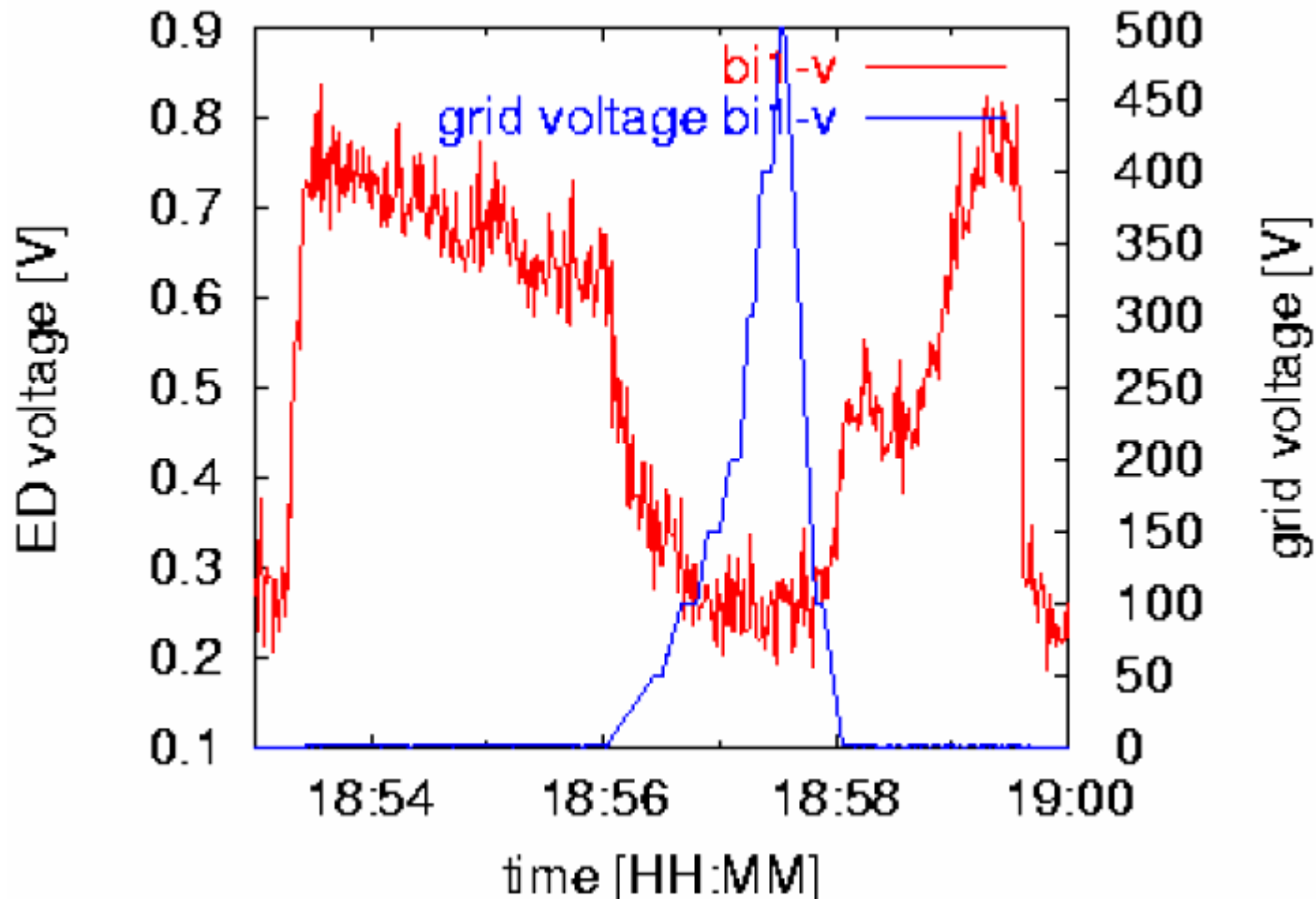


Figure 2: Beam loss and bunch size variation of bunch #40 at transition with $V_{rf} = 300$ kV and $b_{oct} = -3$ unit.

Correlation between e-flux and pressure

- Voltage sweeping to set baseline before ramping



Is it electron?

- Measured electron flux that correlates to pressure and bunch-train dependence of beam loss
- Bunch-train dependence of beam loss, emittance growth, instability growth
- Trailing-edge beam loss
 - A definitive measurement would be tune shift along the bunch train
 - Previously measured at injection

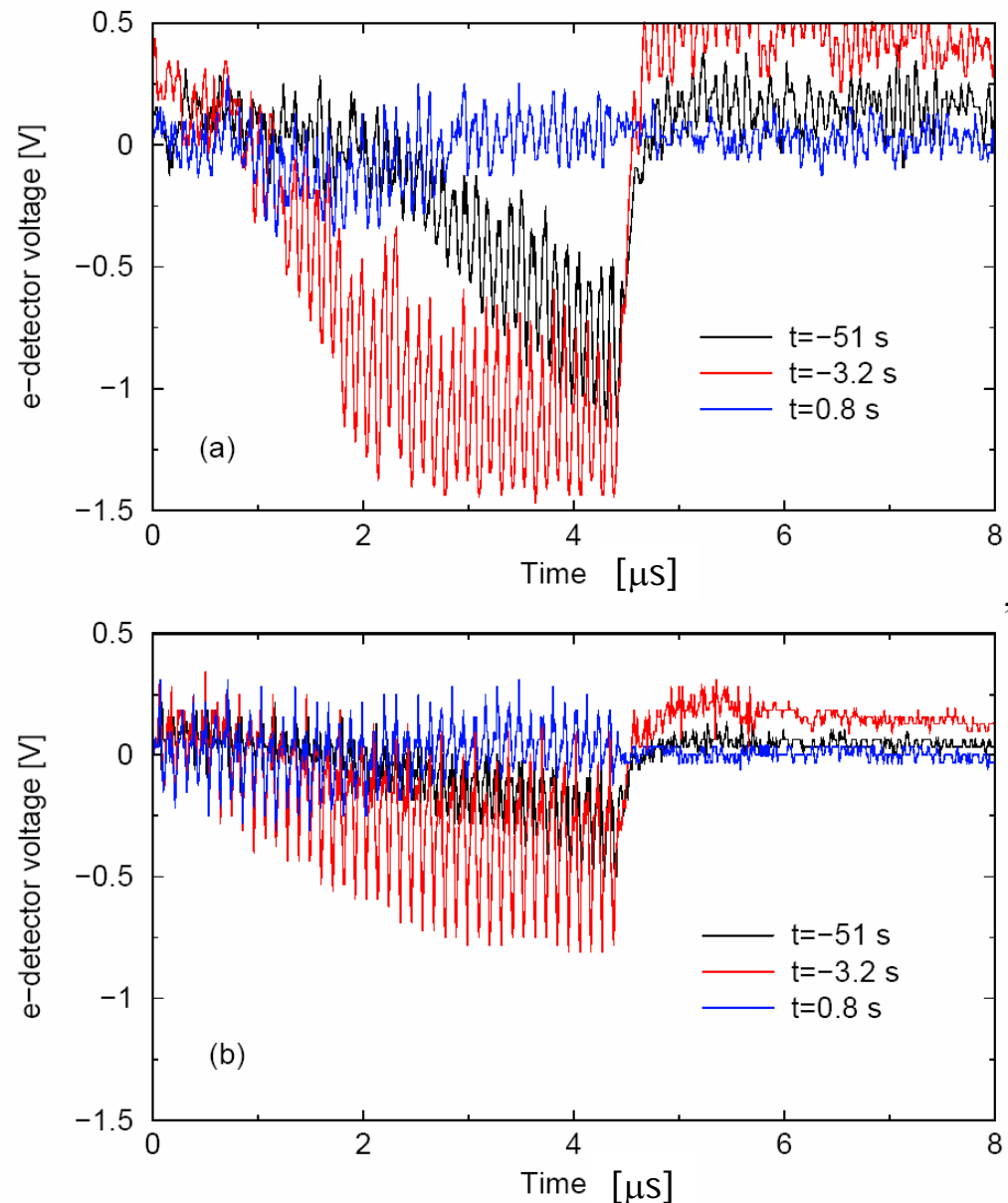
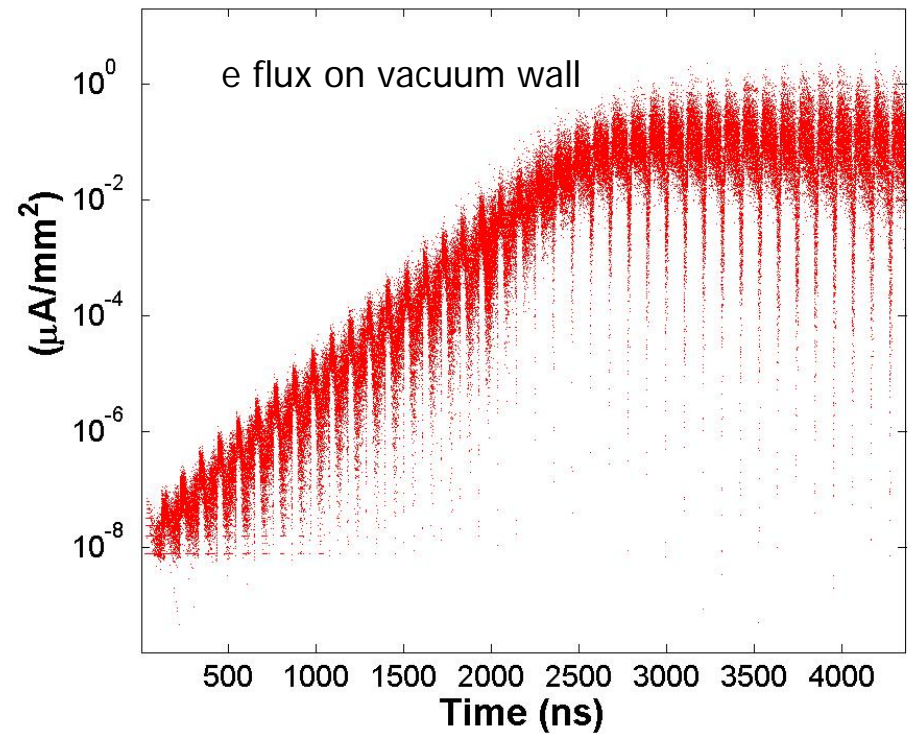
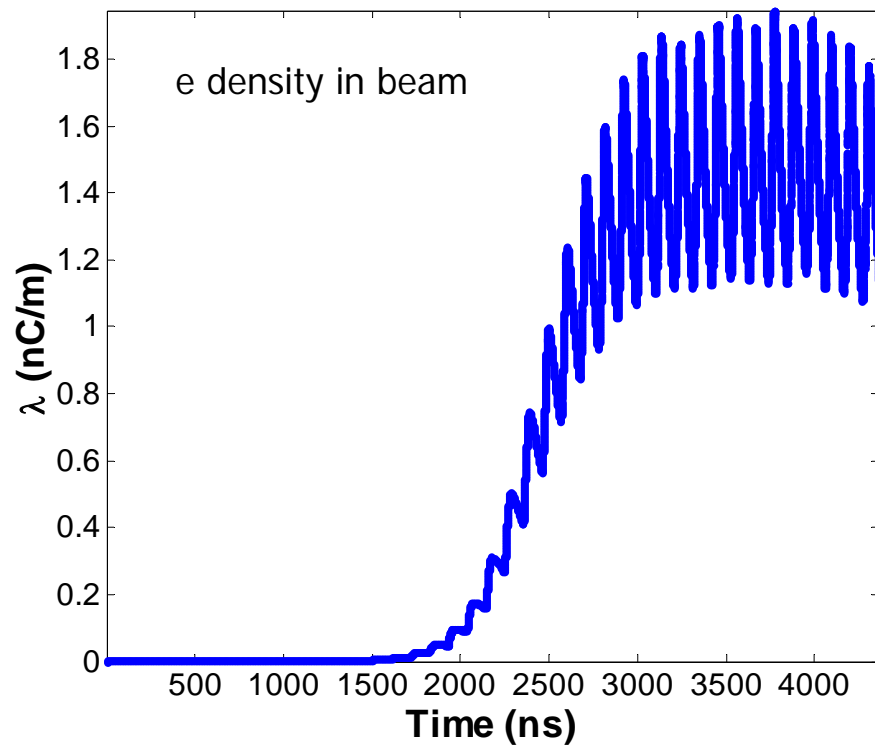


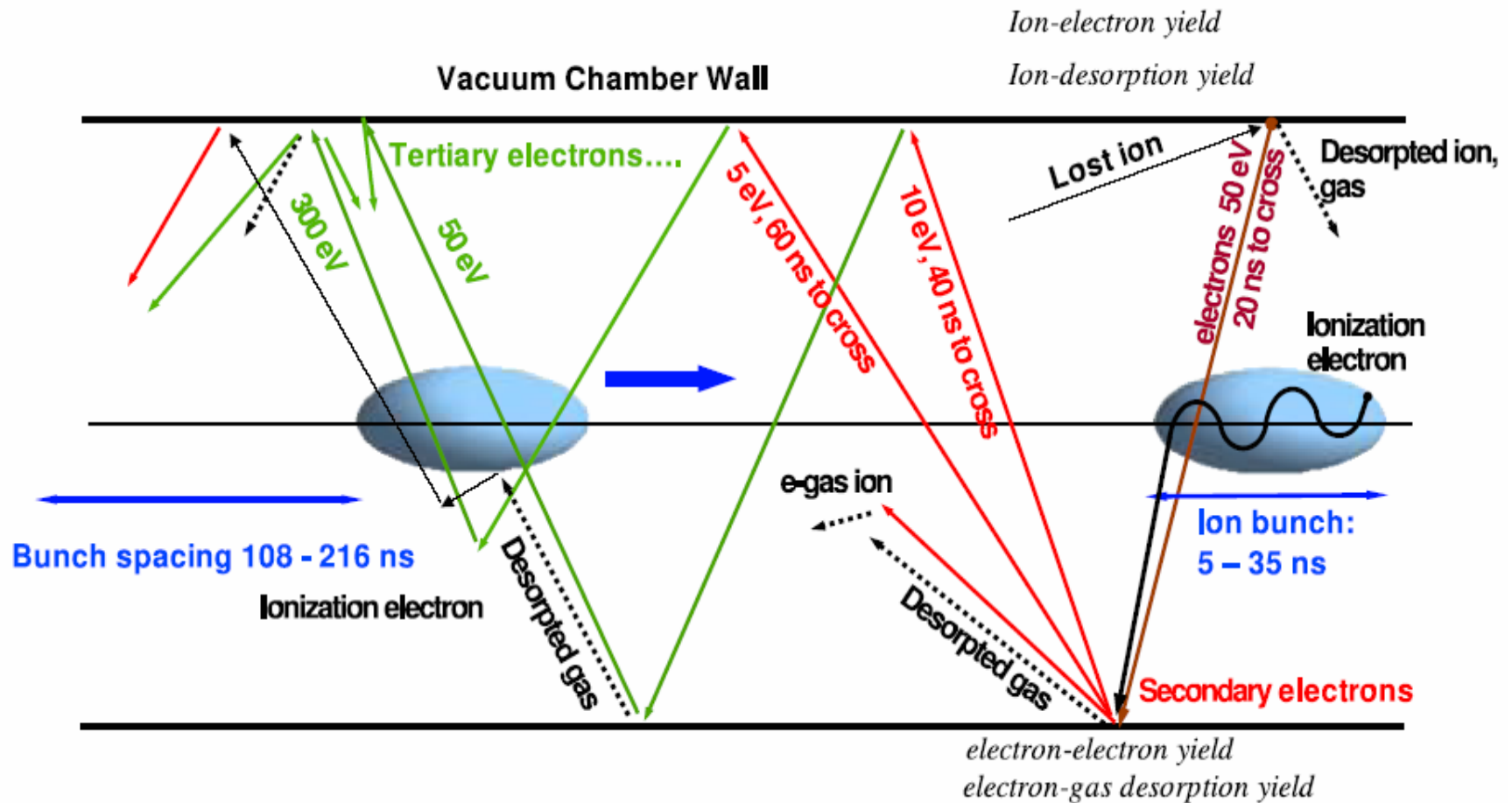
Figure 10: e -flux measured in the (a) horizontal and (b) vertical directions near γ_T . An ac-coupled amplifier is used with a low-frequency cut-off of about 300 kHz. The grid is not biased. The collector is biased at 50 - 100 V positive.

CLOUDLAND simulation (L. Wang)

- Simulation of “realistic” condition with peak secondary yield near 1.8, and non-zero yield at zero energy
- Electron build-up along the beam bunch train
- “Easily” reproduces electron flux observations regarding electron build-up and saturation

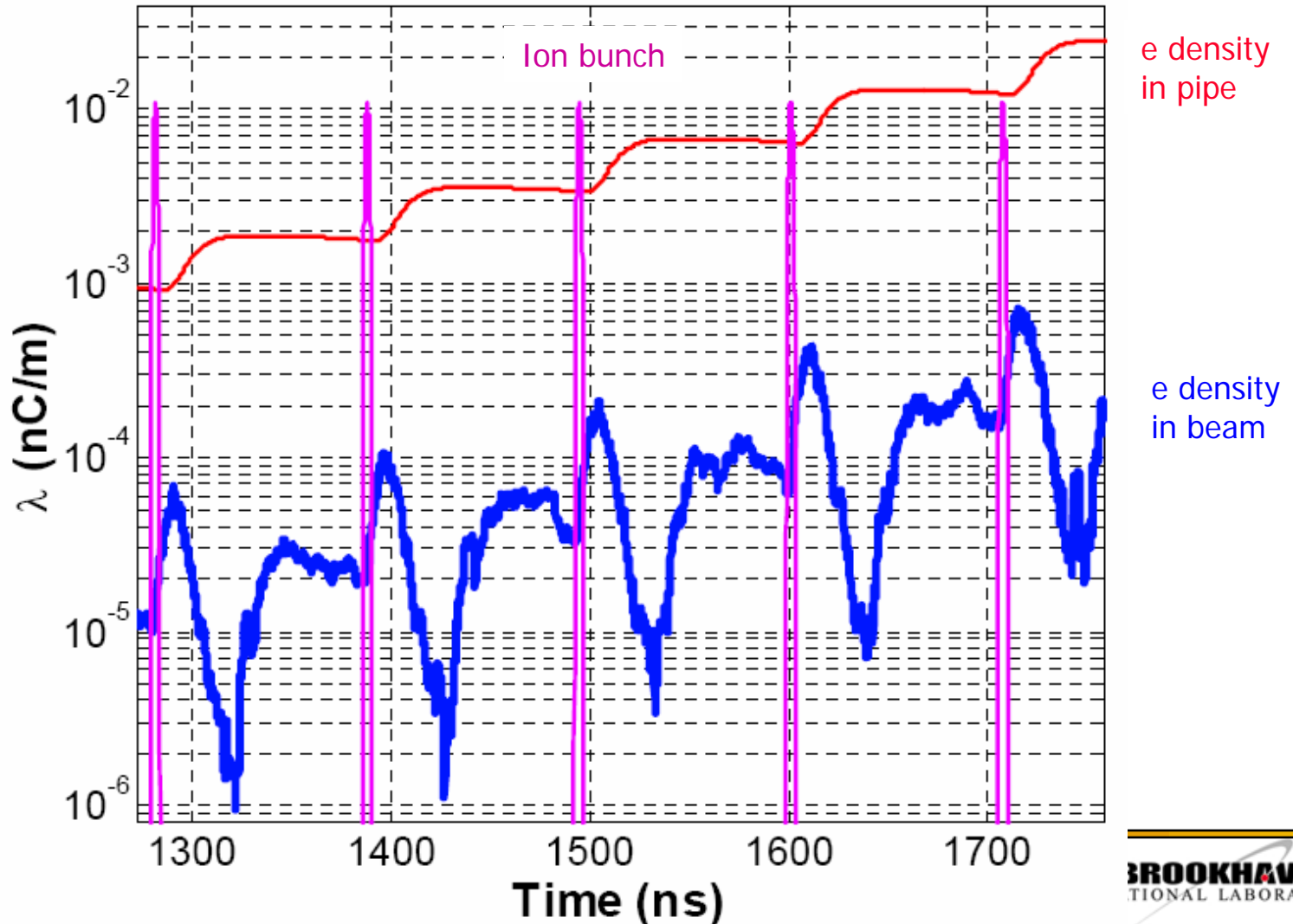


Beam-driven electron multipacting



Simulation: multi- & single bunch effects

- 3 times higher electron density at the tail than that at the head of the ion bunch



(L. Wang)

e-cloud parameter regime (2005)

- Single beam (blue), up to 41 bunches, 3-bucket, 108 ns spacing
- Cu, 5×10^9 per bunch; varying RF voltage and octupole strength

Table 1: RHIC parameters during year 2005 *e*-I study.

Ring revolution period	12.79	μs
Aperture, IR (2/6/8/10, 4/12)	7, 12	cm
Aperture (arc, triplet)	7, 13	cm
Beam species	Cu ²⁹⁺	
Energy, injection - top	9.8 - 100	GeV/u
Transition energy, γ_T	22.9	
Bunch intensity	5×10^9	
Bunch center spacing	108	ns
Bunch length at transition, full	~ 5	ns
Electron bounce frequency	~ 400	MHz
Peak bunch potential	~ 1.6	kV
e^- energy gain upon acceleration	~ 300	V

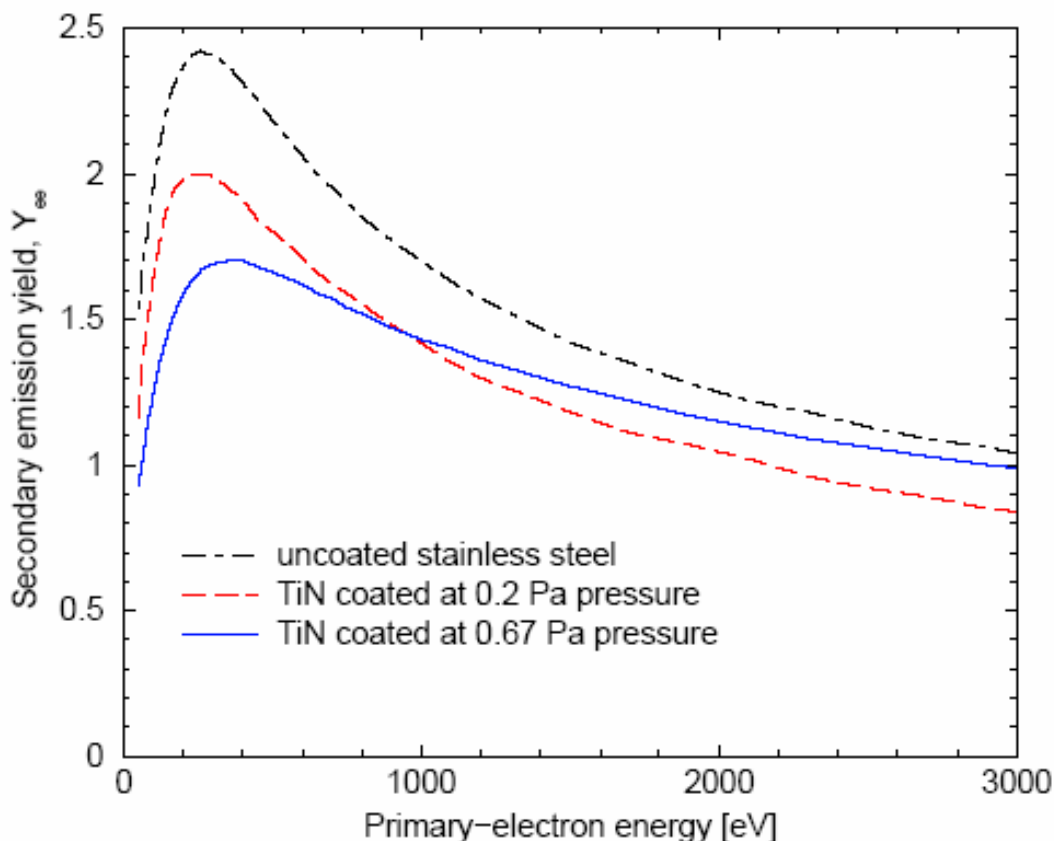
e-cloud multipacting mechanism

- Intermediate-regime multipacting condition:

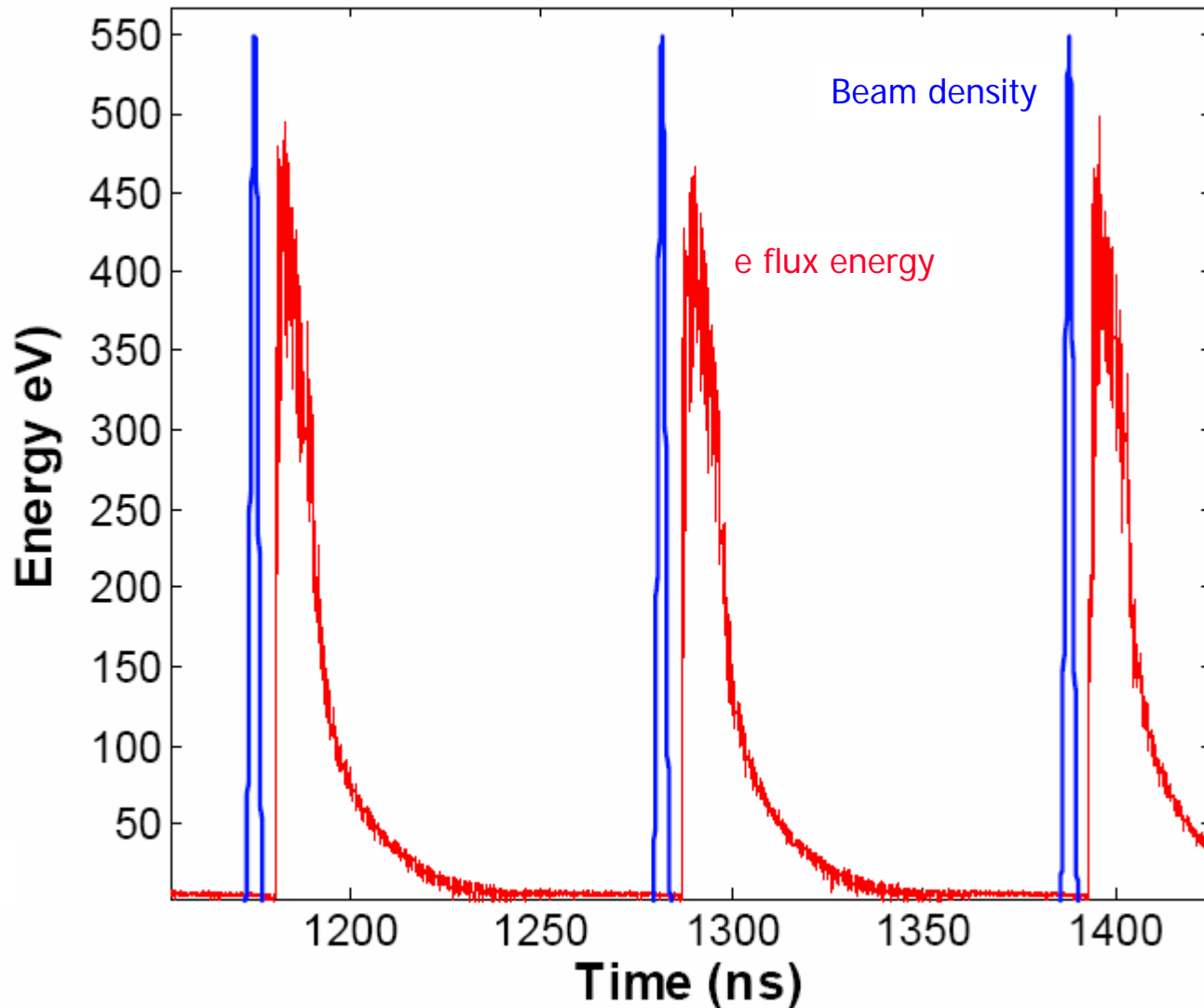
$$Y_{ee,C} \equiv \prod_{i=0,1,\dots,N_{ee}} Y_{ee,i} > 1$$

where

$$Y_{ee,0} > 1, \text{ and } Y_{ee,i} < 1 \text{ for } i = 1, \dots, N_{ee}$$



Electron energy & SEY (simulation)



(L. Wang)

Beam loss vs. bunch sequence

- Puzzle: why the first-bunch beam loss is much higher than nominal, 216 ns spacing case?

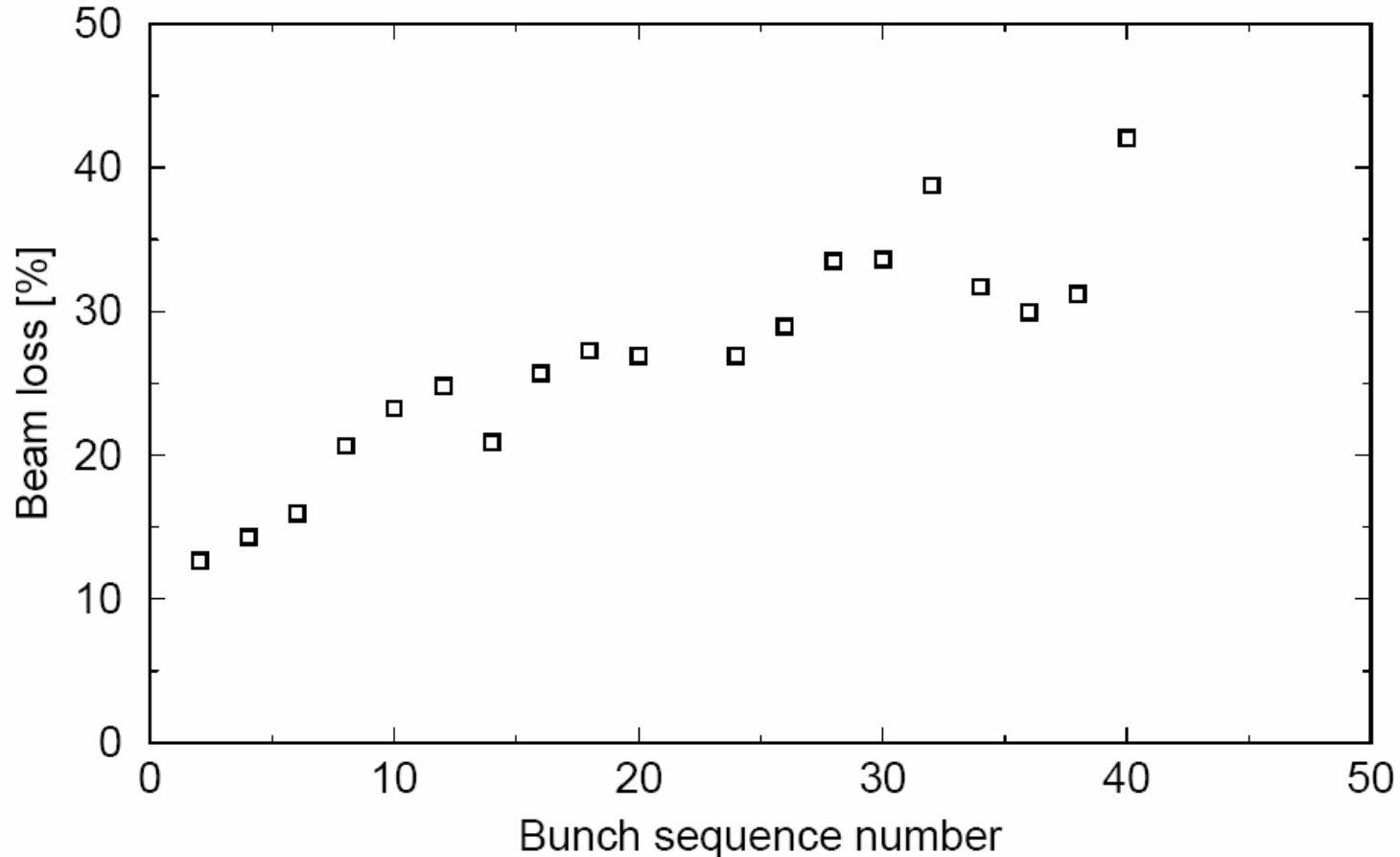
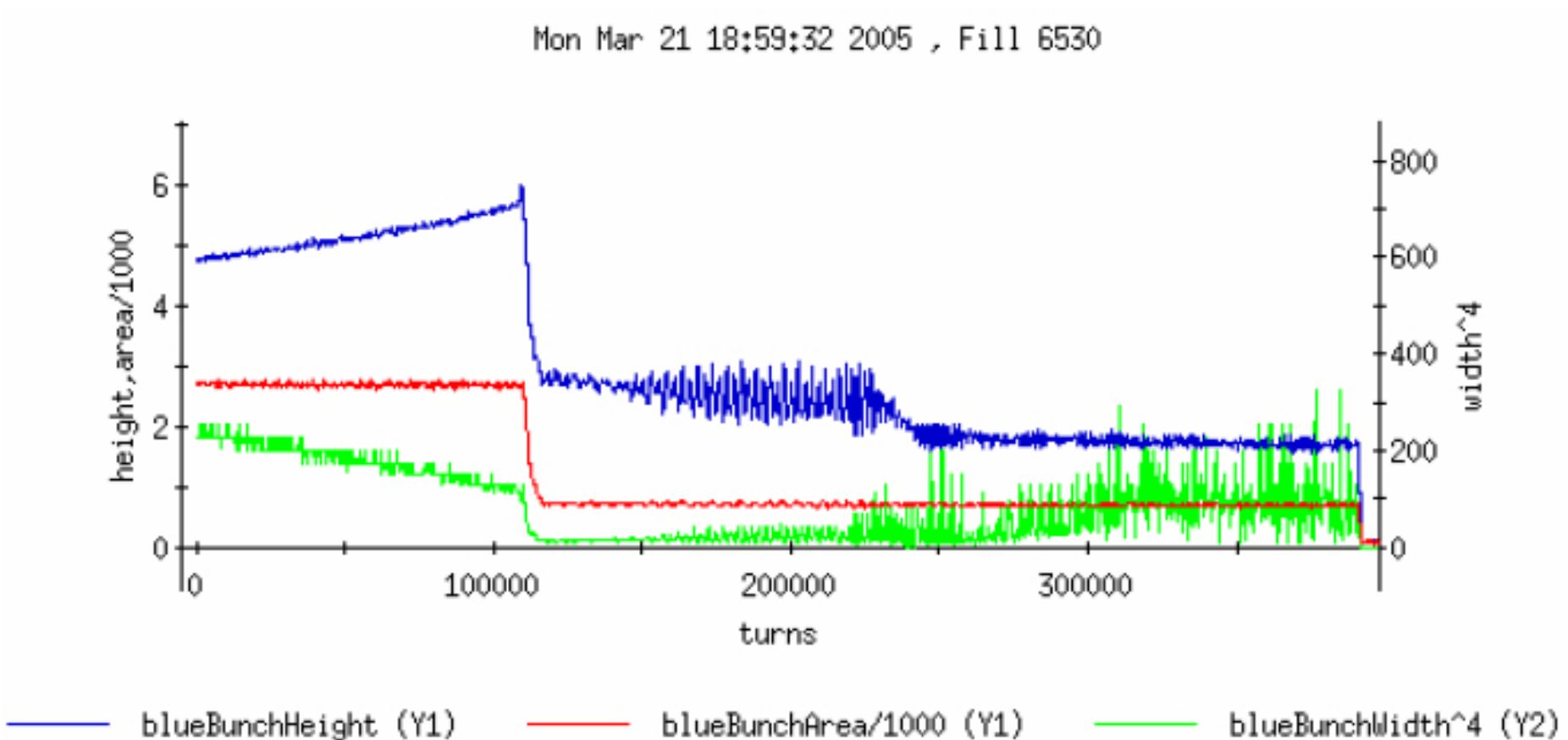


Figure 3: Beam loss at transition as a function of bunch sequence number with $V_{rf}=200$ kV and $b_{oct} = -3$ unit.

#6530 WCM of bunch #40

- Tracked one bunch across transition every 250 turns
 - Beam loss: 73% on bunch #40; 52% averaging over 41 bunches



Instability seen by coherence monitor

- Transverse instability occurs about 10 ms after transition for about 100 ms

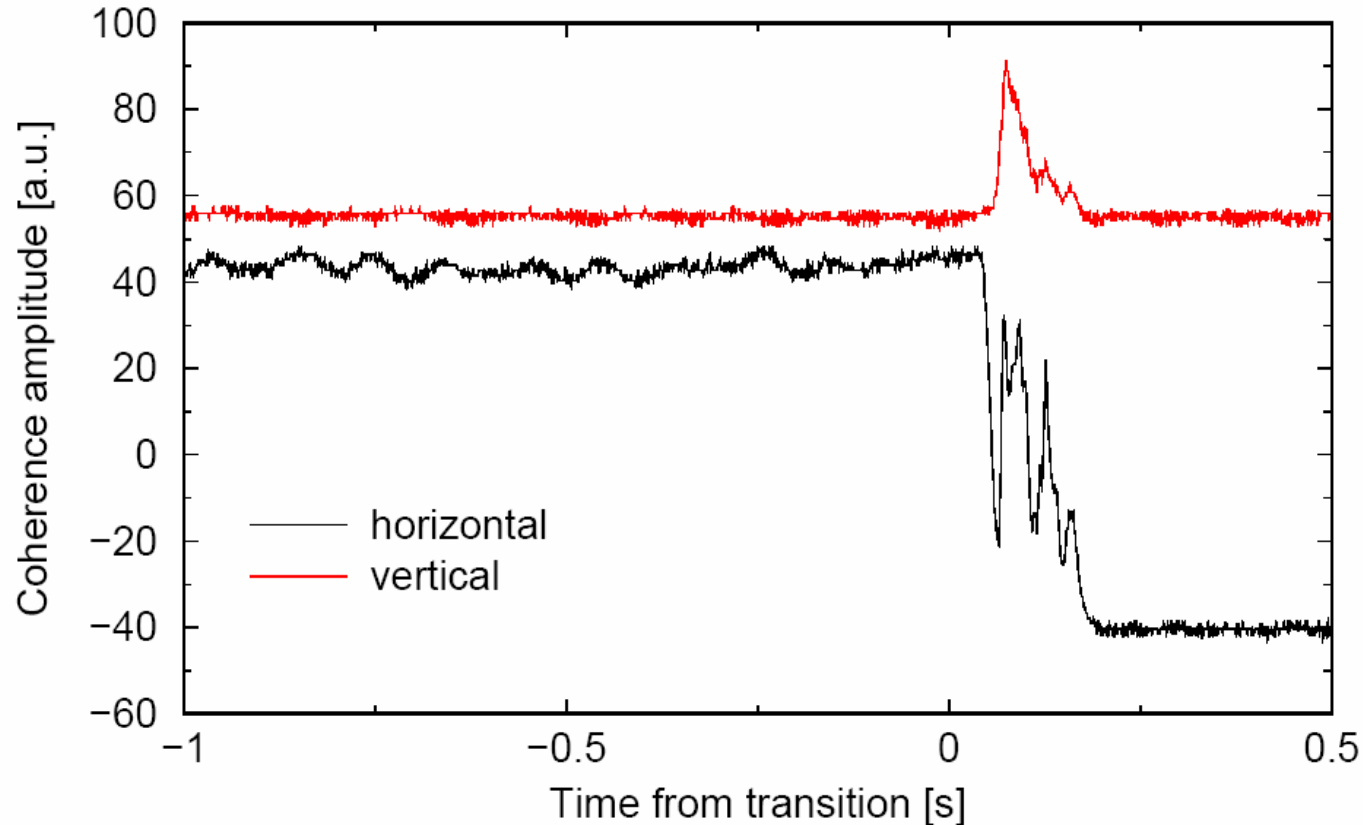
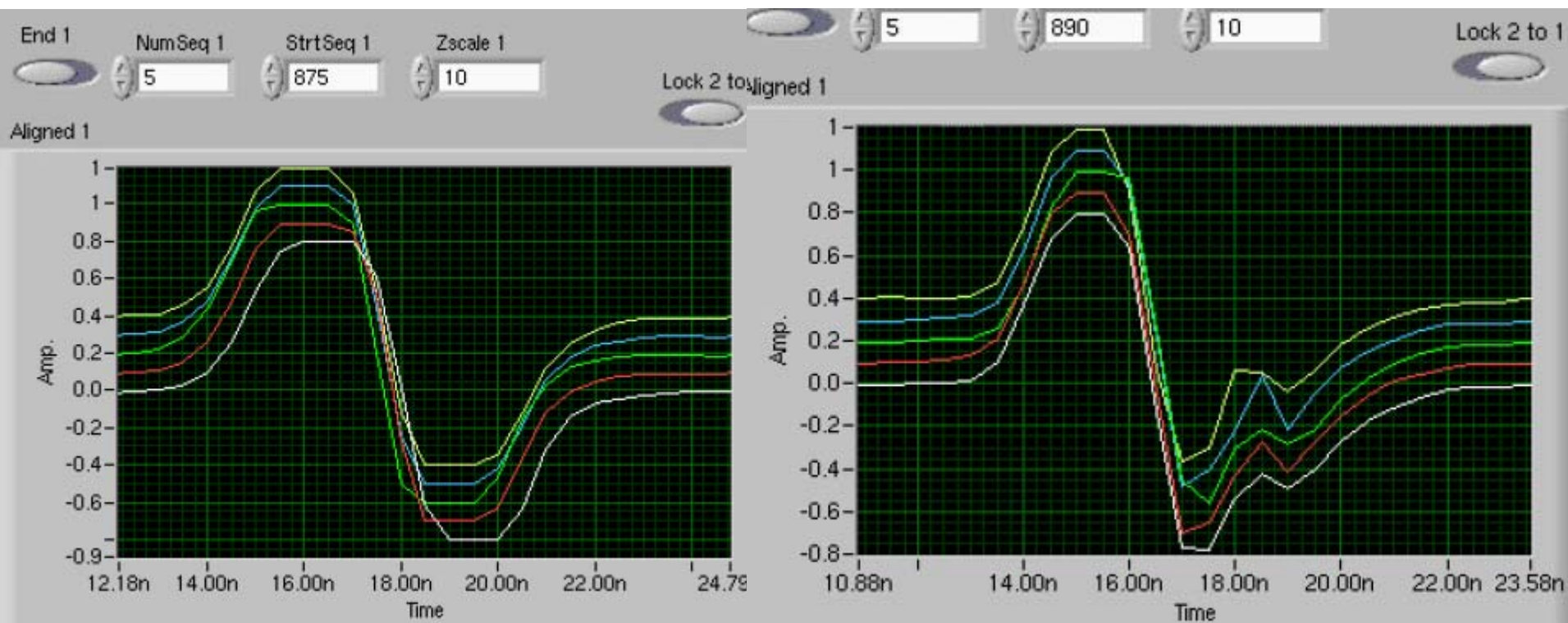


Figure 5: Coherence signal of bunch #40 from the turn-by-turn BPM data. The horizontal instability signal is within a step caused by the orbit shift due to γ_T -jump.

Button BPM (1)

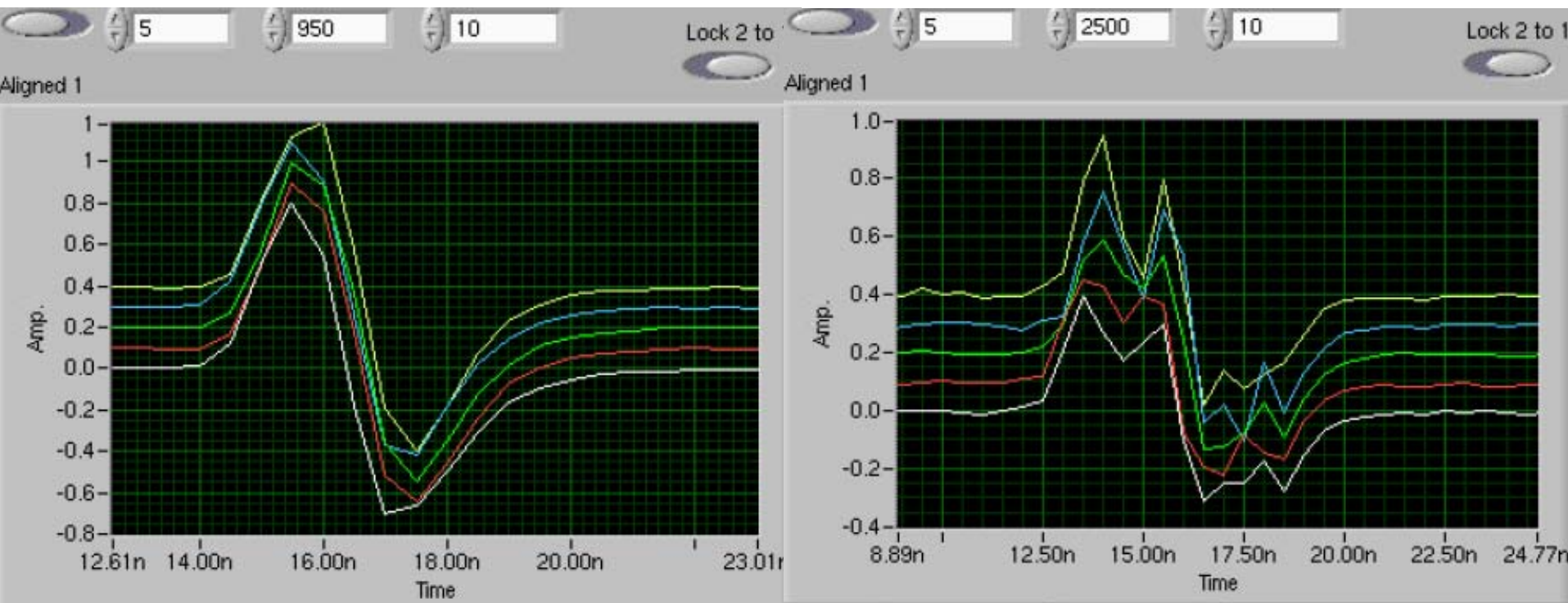
- Trailing edge structure starts about 10 ms after transition, lasts for about 50 ms
- Time scale corresponds to WCM's

(R. Lee, M. Blaskiewicz)

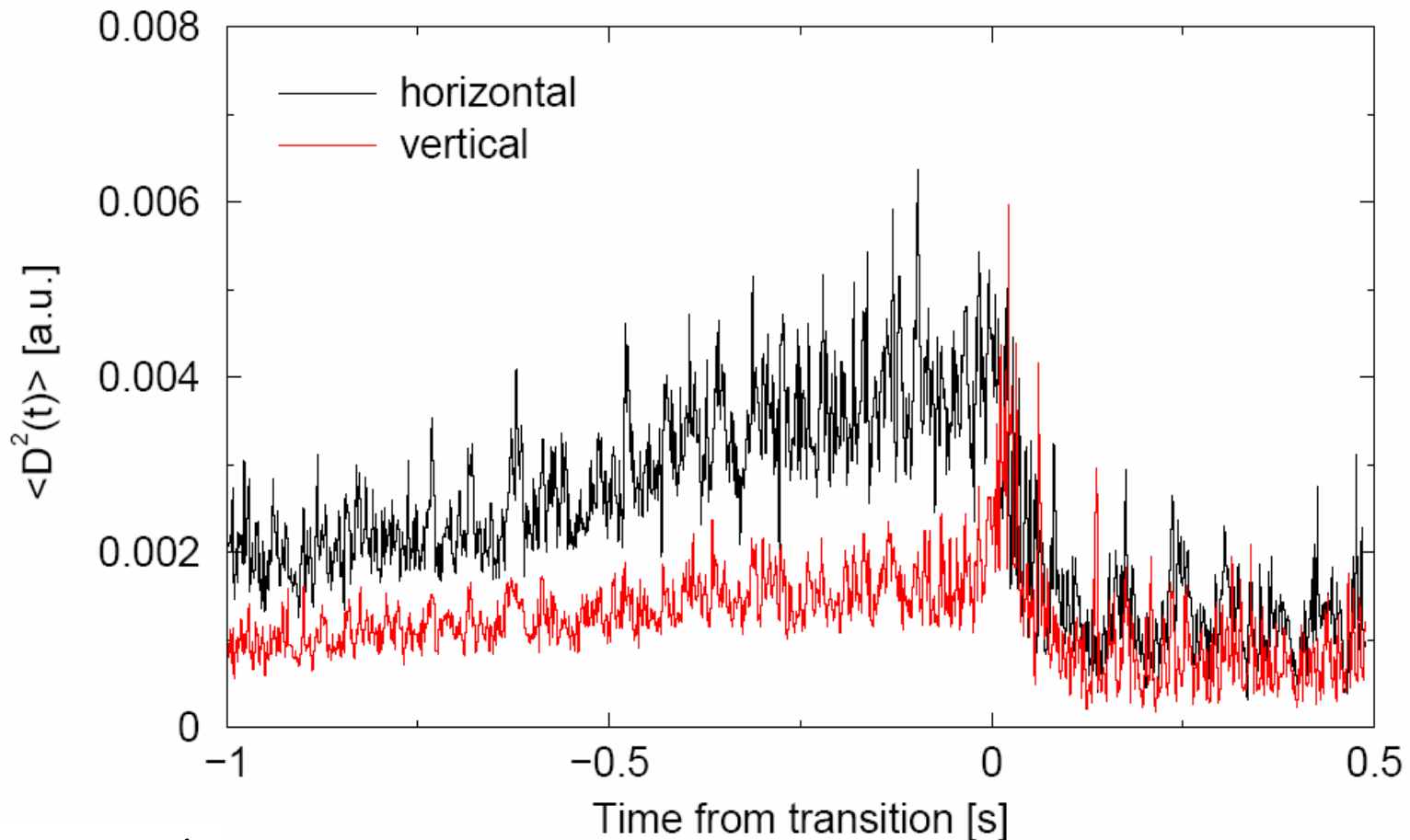


Button BPM (2)

- The peak position oscillates afterwards
- High frequency structure further develops across the whole bunch corresponding to WCM observation of micro-bunching



Instability seen on button BPM



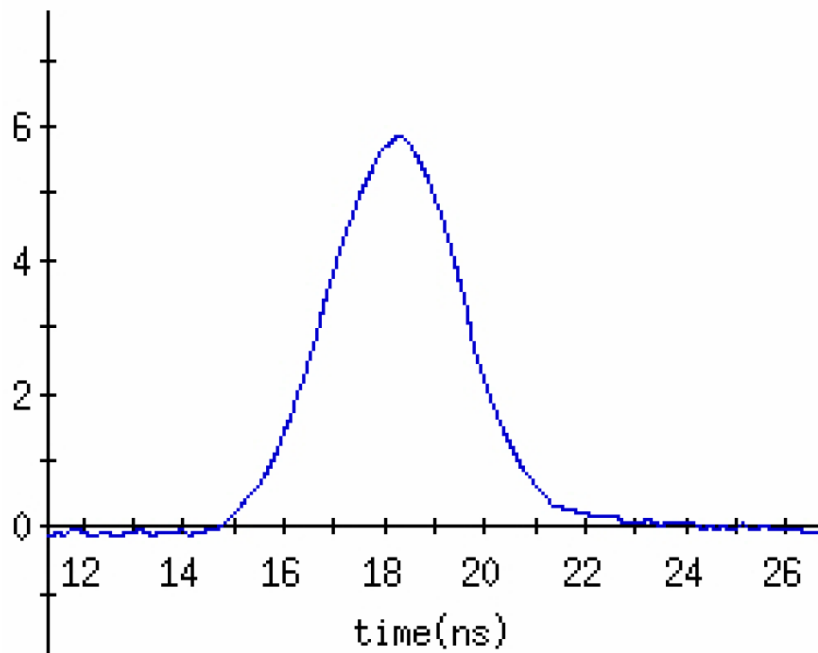
(M. Blaskiewicz)

Figure 6: Mean square of the difference displacement measured by the “button” BPM sampling every 0.5 ns.

WCM longitudinal profiles (1)

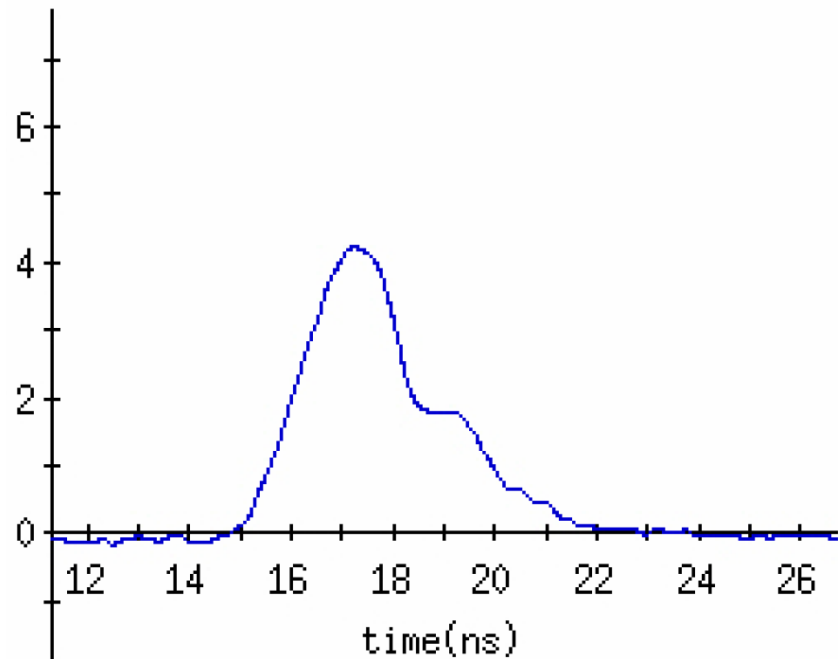
- During unstable period, high frequency (~ 400 MHz) structure developed on the trailing edge of the bunch #40
- Trailing edge beam break-up (BBU)

Turn 109750



— bunchProfile

Turn 111500

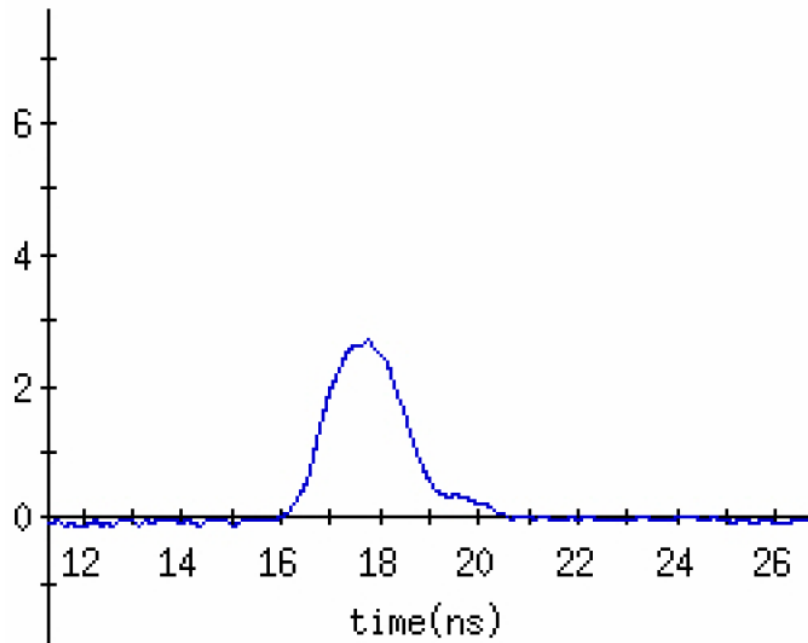


— bunchProfile

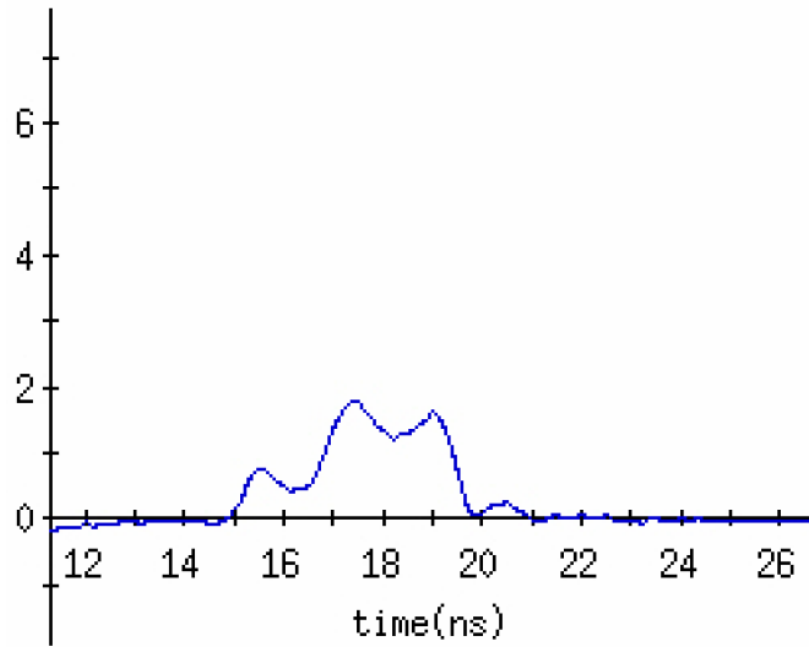
WCM longitudinal profiles (2)

- The trailing edge structure lasts for longer than 50 ms
- About 1.7 seconds later, micro-bunching occurs across the whole bunch

Turn 137250



Turn 246000



— bunchProfile

— bunchProfile

Beam loss at the bunch trailing edge

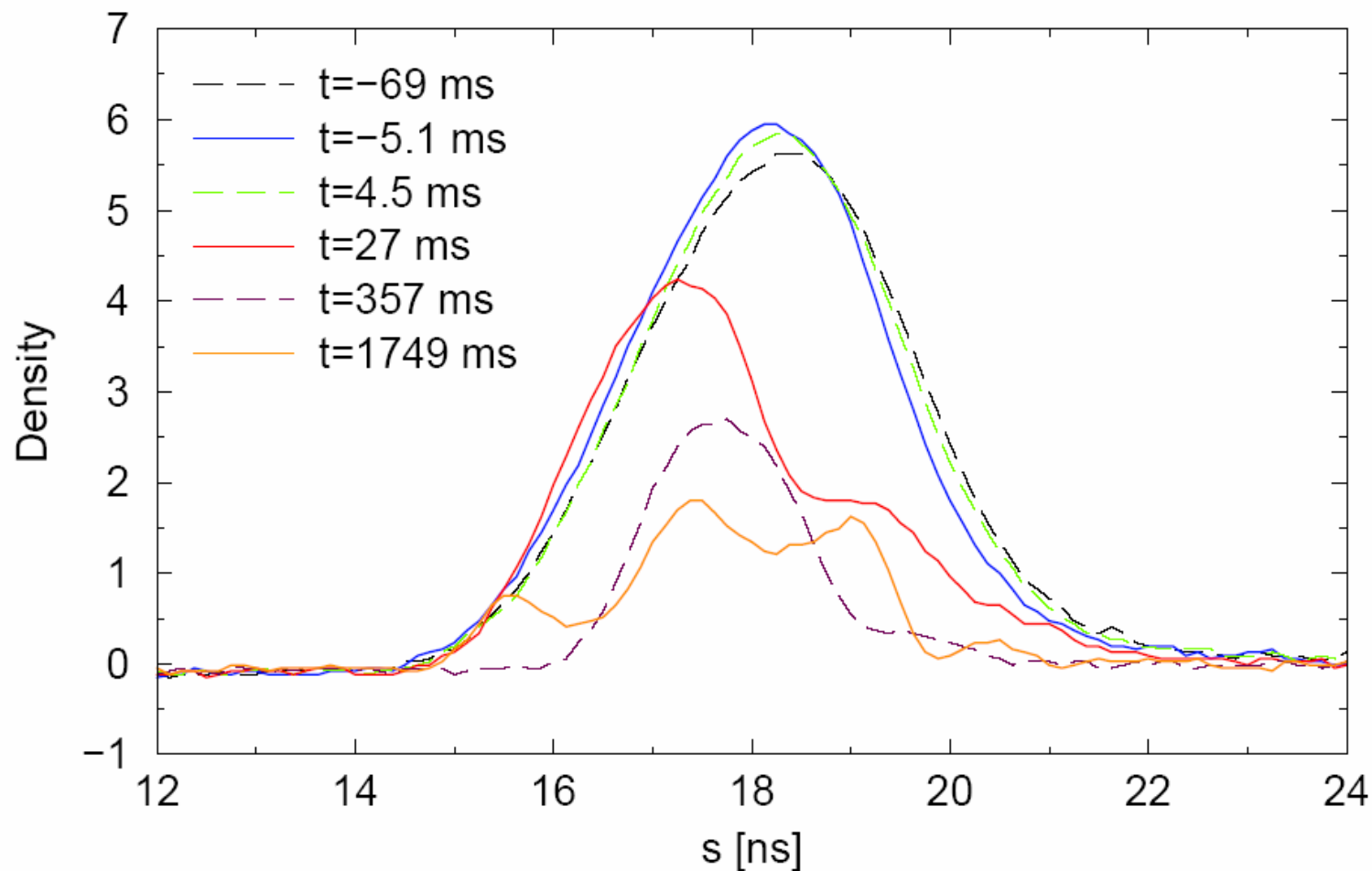


Figure 9: Evolution of the longitudinal profile upon the beam loss near γ_T with $V_{rf}=300$ kV and $b_{oct} = -4$ unit.

Transverse emittance growth

- When beam loss is relatively moderate, emittance growth shows bunch train dependence
- It is difficult for IPM to work near transition (electron? Loss/pressure/background?)

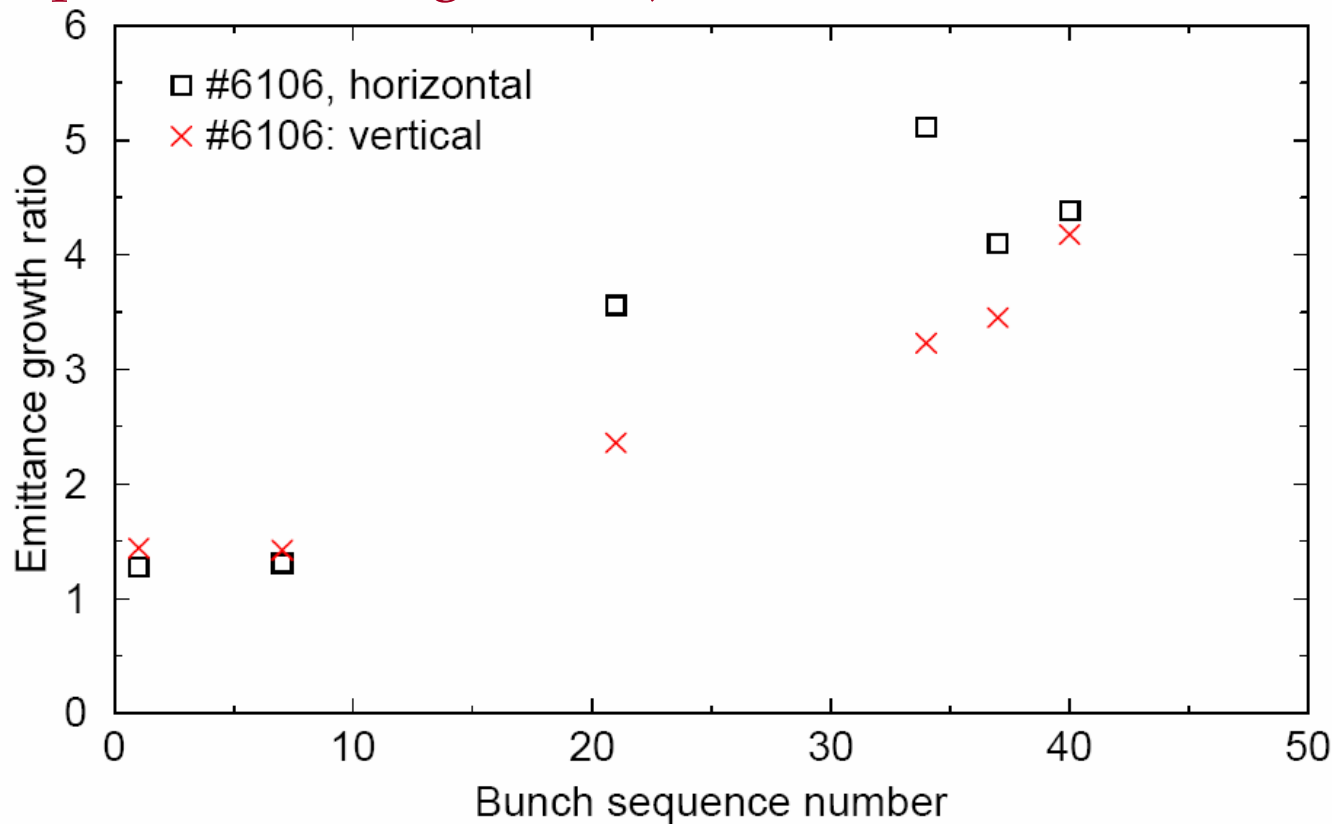
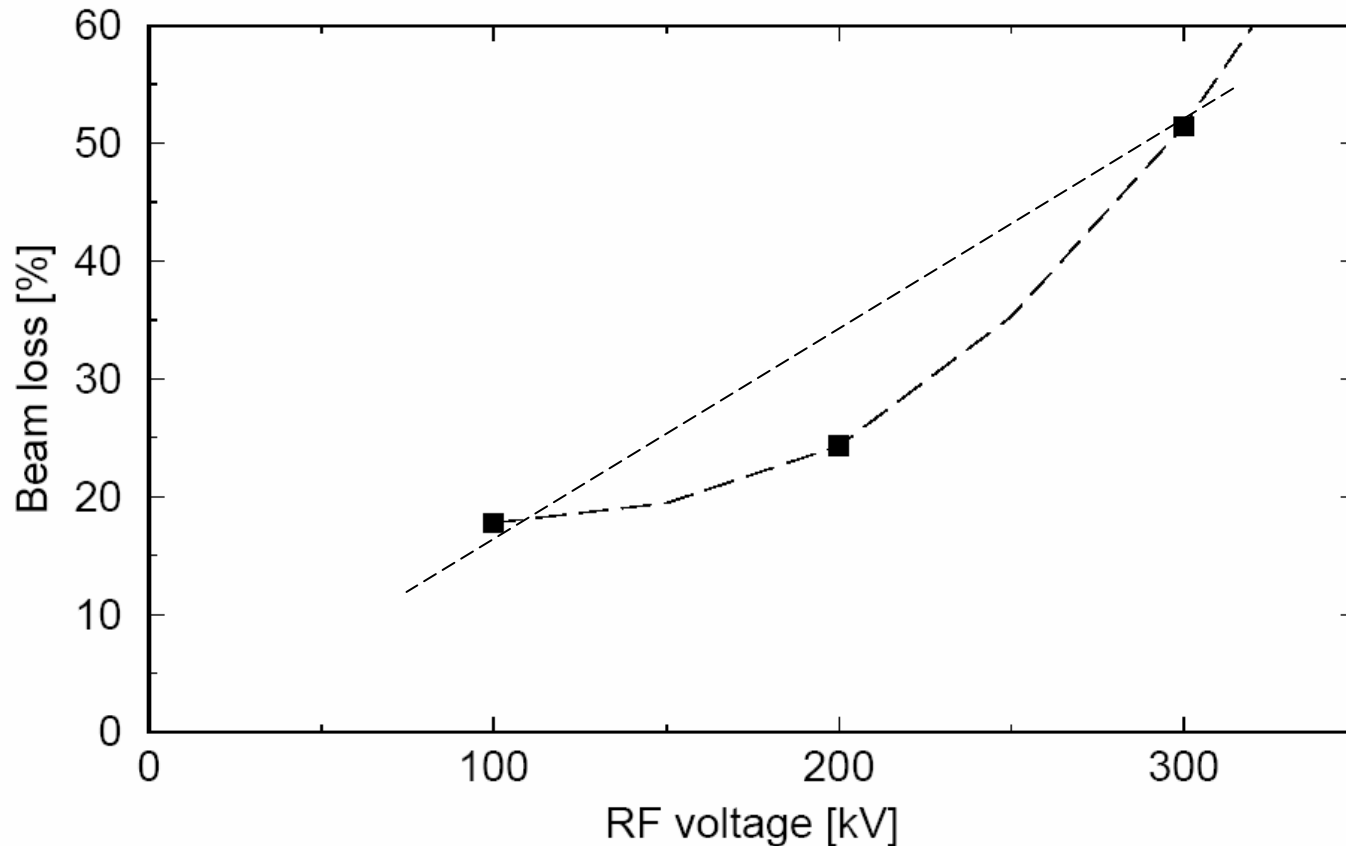


Figure 8: Bunch train dependence of the beam emittance growths at γ_T with $V_{rf}=100$ kV and $b_{oct} = -4$ unit.

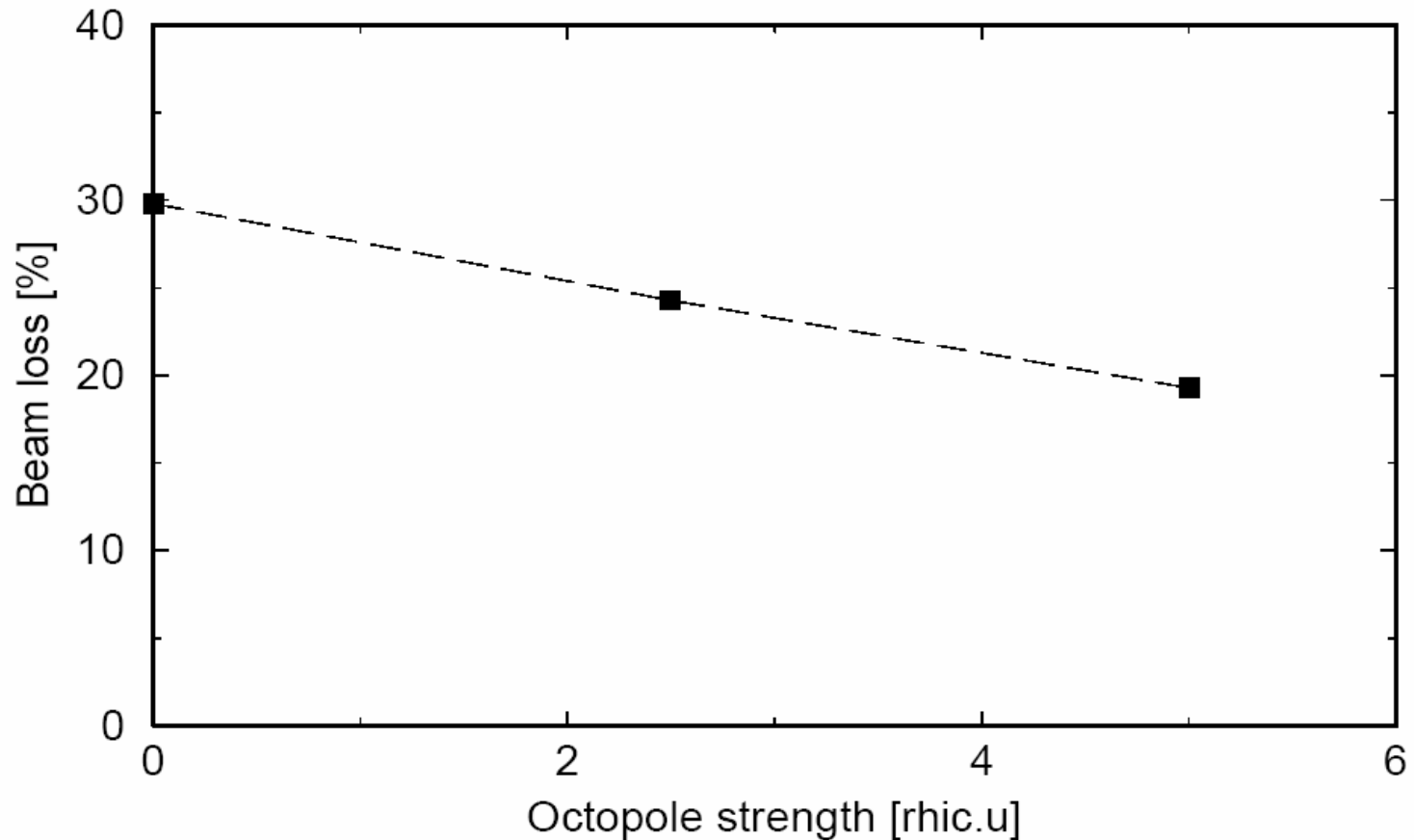
RF voltage dependence (strong)

- Lower RF voltage: no coherence; lower beam loss; lower e-flux
- RF manipulation can possible cure the problem!



Octupole dependence (weak)

- Higher octupole strength: lower loss, lower coherence



— RHIC R Figure 7: Average beam loss at transition as a function of the octupole magnet strength $|b_{oct}|$ with $V_{rf} = 200$ kV.

Mitigation

- NEG coating/solenoid in warm section
 - 30% solution
- RF manipulation
 - RF voltage choice
 - Dual-harmonic RF
 - Induction RF
- Damping enhancement
 - Octupoles
 - Fast chromaticity jump at transition?
 - Fast, wide-band damper?
- Multiple bunch gaps?
- Beam conditioning?

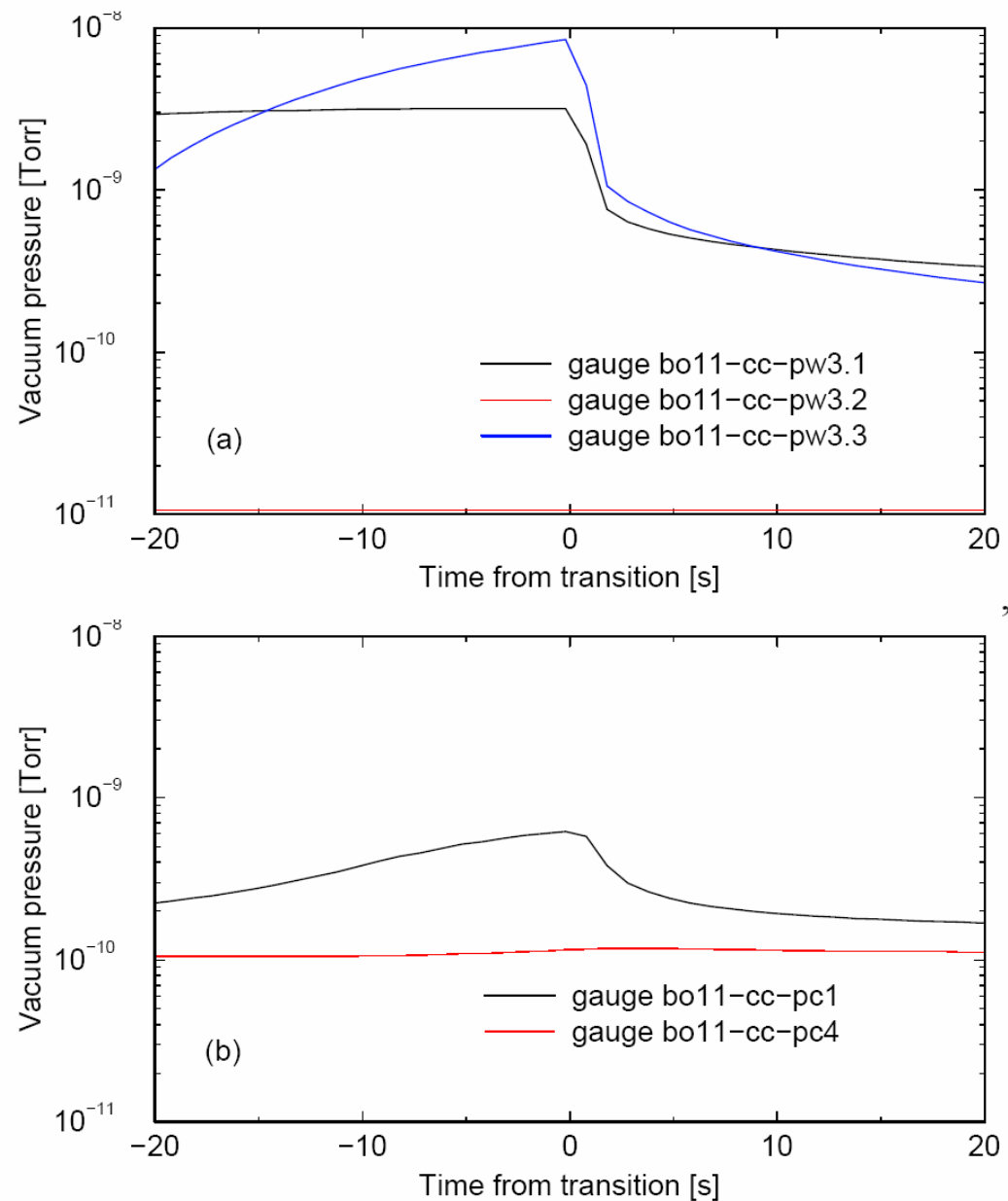
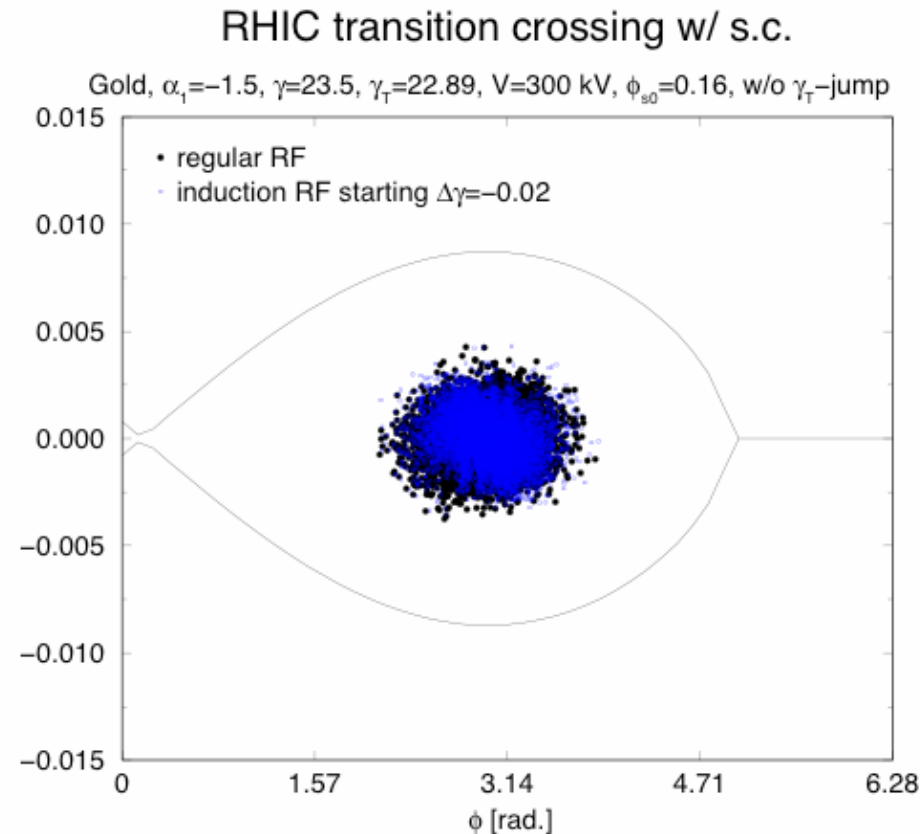
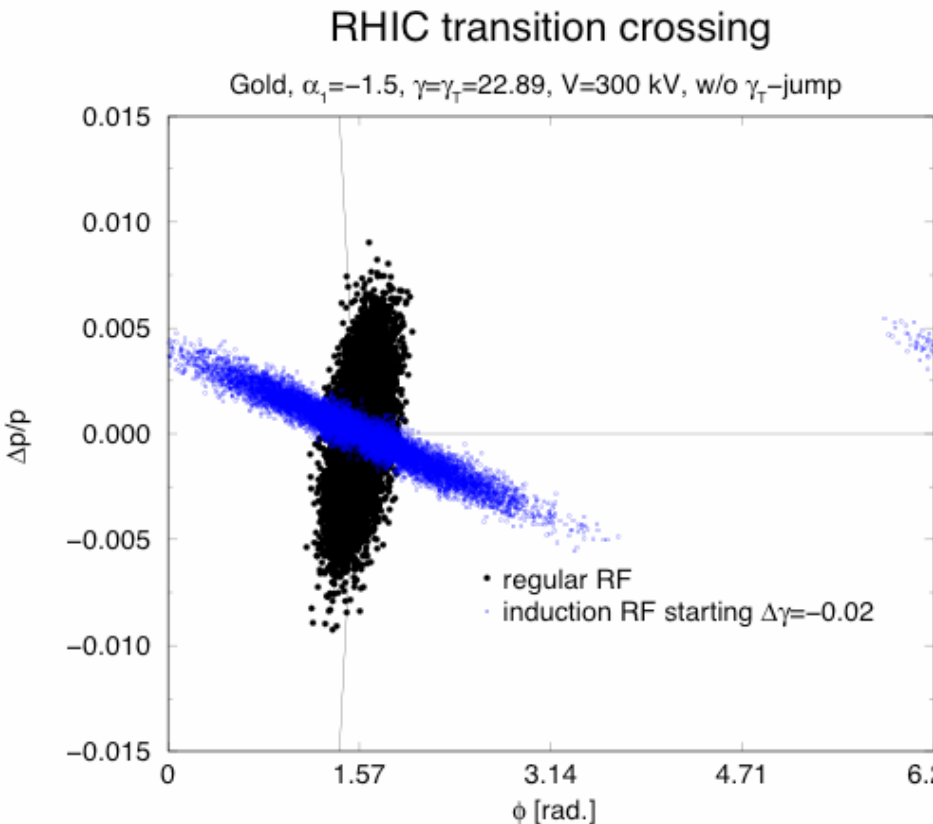


Figure 11: Vacuum pressure rise in the (a) warm and (b) cold region of the ring. Pressure on gauge bo11-cc-pw3.2 located between the two NEG-coated pipes does not rise.

Focusing-free transition crossing

- Replacing regular RF with FFTC induction cavity at transition
- May need to compensate lattice linearity to be reversible



Open questions

- Why even the first bunch in the train suffers a beam loss much higher than the nominal?
 - One possibility is the multipacting-related gas scattering. More detailed logging of the vacuum pressure (every 0.1 s instead of 1s) may clarify the mechanism.
- Does the instability alone causes more than 70% beam loss in 0.1 s? what are the principle instability modes? and why beam loss and the transverse instability occur only after but not before transition?
 - A possible explanation yet to be verified is a sizable tune shift due to e-cloud coupled with a transition-jump lattice close to resonance. e-detector data needs to be logged in finer steps (1 ns instead of 10 ns) to explore e-cloud generation within each single bunch.

Comments

- Set up PLL tune measurement on the bunch train head (1/3) and tail (1/3). Al stated that there is a big shift in tune between the head and tail of the 40-bunch train though many of us did not understand the plot yet.
- The e-detector logging could be more detailed, 1 ns instead of 10 ns. That way we could have detailed e-signal within a bunch to compare rising/trailing edge difference.
- The IPM manager stopped about 15 sec before transition even though Roger/Steve were present. Perhaps the electron signal was too strong for IPM.
- The M-turn BPM did not show meaningful signal according to Todd.
- The vacuum pressure 100 ms logging data was absent (not triggered?)
- The Artus tune measurement along the bunch train did not show observable tune shift at injection even though Todd twice ran his script.
- We should have used 200 kV RF voltage at transition instead of 300 kV. Last time when using 200 kV at injection through transition (fill #6250) a mysterious instability at injection was correlated to electron cloud (bunch train dependent beam loss, correlation to e-flux, coherence). But if we start with 300 kV and lower to 200 kV that would work.
- We could also measure bunch train tune with PLL at injection but didn't have time.
- We could later calibrate coherence signal with AC dipole.

Conclusion

- Electron cloud is a serious obstacle on RHIC's upgrade path
- Mitigation is not trivial, e.g. using induction RF across transition
- More simulation and study is needed, especially on electron-ion interaction

PLL tune measurement

- Tune tracked well through transition, but
- Tracked H-plane of head and V-plane of tail of the bunch train

